

PATENT ABSTRACTS OF JAPAN

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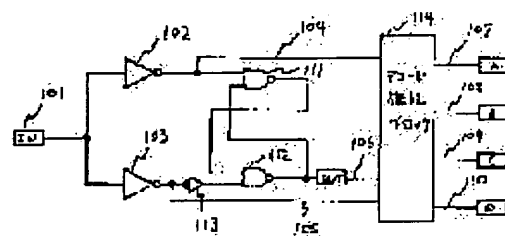
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(54) TEST SIGNAL PRODUCING DEVICE

(57)Abstract:

PURPOSE: To perform tests by a number of times larger than the number of input terminals by providing a function block which decodes the outputs of a plurality of semiconductor elements having different logic levels and a Schmitt trigger inputting function block.

CONSTITUTION: When the voltage of an external input signal 101 is lower than the logic level (lower than the logic level of a semiconductor element 102) of a semiconductor element 103, both the elements 103 and 104 so judge that their input levels are low and output inverted 'H' signals 105 and 104. Both outputs are inputted to logic circuits 111-113 constituting an RSFF and the output 106 of a Schmitt trigger inputting circuit also becomes an 'H' signal. These outputs are converted by means of a decoding function block 114 and only a decoded output 107 is outputted at an 'H' level. As a result, the block 114 generates four kinds of decoded signals 107-110 by combining the outputs 106-104 in accordance with the inputting voltage of the signal 101 and the rising and dropping variation of the voltage. Therefore, a total of three kinds of circuit states can be set for selective tests except the normal operating state.



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